



# On Three Hypotheses Robust Detection Design Under Mismatch

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**Abstract:** Generalizing the result of D. Kazacos for two hypotheses we consider the ternary detection problem of the Neyman-Pearson type under mismatch. For the case of independent ... [View more](#)

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Generalizing the result of D. Kazacos for two hypotheses we consider the ternary detection problem of the Neyman-Pearson type under mismatch. For the case of independent identically distributed observations the sufficiency condition of existence of test with an exponentially decreasing probability of error is formulated in terms of the new notion of “divergence for three distributions in certain order”.

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**Contents****I. Introduction**

One of the general problems in statistics is the choice between different explanations (hypotheses) regarding the studied object.

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